

**Search Notes**

Application/Control No.

10/764,515

Examiner

David E. Martinez

Applicant(s)/Patent under  
Reexamination

LEE, CHUN-LIANG

Art Unit

2181

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
710	62,100	2/1/2007	DM
710	305,315	2/1/2007	DM
Databases: US Patents, US PGPUBS, USOCR, EPO, JPO, Derwent,		2/1/2007	DM

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East see attached	2/1/2007	DM
710/62,64,72,100,300,305,306,313,315.ccls. with keywords and text search	2/1/2007	DM
Databases: US Patents, US PGPUBS, USOCR, EPO, JPO, Derwent, IBM_TDB.	2/1/2007	DM
eDan inventor search	2/1/2007	DM